

Librería
Bonilla y Asociados
desde 1950



Título:

Autor:

Precio: \$1788.00

Editorial:

Año: 2006

Tema:

Edición: 3ª

Sinopsis

ISBN: 9780471739067

The Third Edition of the internationally lauded Semiconductor Material and Device Characterization brings the text fully up-to-date with the latest developments in the field and includes new pedagogical tools to assist readers. Not only does the Third Edition set forth all the latest measurement techniques, but it also examines new interpretations and new applications of existing techniques.

Semiconductor Material and Device Characterization remains the sole text dedicated to characterization techniques for measuring semiconductor materials and devices. Coverage includes the full range of electrical and optical characterization methods, including the more specialized chemical and physical techniques. Readers familiar with the previous two editions will discover a thoroughly revised and updated Third Edition, including:

Updated and revised figures and examples reflecting the most current data and information
260 new references offering access to the latest research and discussions in specialized topics
New problems and review questions at the end of each chapter to test readers' understanding of the material